

November 2015

# FQD2N60C / FQU2N60C

# N-Channel QFET<sup>®</sup> MOSFET 600 V, 1.9 A, 4.7 $\Omega$

### **Features**

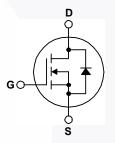
- 1.9 A, 600 V,  $R_{DS(on)}$  = 4.7  $\Omega$  (Max.) @  $V_{GS}$  = 10 V,  $I_D$  = 0.95 A
- Low Gate Charge (Typ. 8.5 nC)
- · Low Crss (Typ. 4.3 pF)
- 100% Avalanche Tested
- RoHS Compliant

# Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.







# **Absolute Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter		FQD2N60CTM / FQU2N60CTU	Unit
$V_{DSS}$	Drain-Source Voltage		600	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		1.9	Α
	- Continuous (T <sub>C</sub> = 100°C)		1.14	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	7.6	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		120	mJ
I <sub>AR</sub>	Avalanche Current (N		1.9	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note		4.4	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5	V/ns
	Power Dissipation (T <sub>A</sub> = 25°C)*		2.5	W
$P_D$	Power Dissipation (T <sub>C</sub> = 25°C)		44	W
	- Derate above 25°C		0.35	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

## **Thermal Characteristics**

Symbol	Parameter	FQD2N60CTM / FQU2N60CTU	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max. 2.87			
D	Thermal Resistance, Junction-to-Ambient (minimum pad of 2 oz copper), Max.	110	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (* 1 in² pad of 2 oz copper), Max.	50		

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQD2N60C	FQD2N60C FQD2N60CTM		330 mm	16 mm	2500 units
FQU2N60C	FQU2N60CTU	I-PAK	Tube	N/A	70 units

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V, } I_D = 250  \mu\text{A}$	600			V
$\Delta BV_{DSS}$ / $\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		0.6		V/°C
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>DSS</sub>		V <sub>DS</sub> = 480 V, T <sub>C</sub> = 125°C			10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 0.95 A		3.6	4.7	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 0.95 A		5.0		S
	ic Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		180	235	pF
Coss	Output Capacitance	f = 1.0 MHz		20	25	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			4.3	5.6	pF
Switchi	ing Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 300 \text{ V}, I_D = 2 \text{ A},$		9	28	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		25	60	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			24	58	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	/	28	66	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 480 V, I <sub>D</sub> = 2 A,	-	8.5	12	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		1.3		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4)		4.1		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				1.9	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				7.6	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 1.9 A			1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2 A,	-	230	- 1	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>F</sub> / dt = 100 A/μs		1.0		μС

#### NOTES

<sup>1.</sup> Repetitive Rating : Pulse width limited by maximum junction temperature.

<sup>2.</sup> L = 56 mH, I $_{AS}$  = 2 A, V $_{DD}$  = 50 V, R $_{G}$  = 25  $\Omega$ , starting T $_{J}$  = 25°C.

<sup>3.</sup>  $I_{SD} \le 2$  A, di/dt  $\le 200$  A/ $\mu$ s,  $V_{DD} \le BV_{DSS,}$  starting  $T_J$  = 25°C.

<sup>4.</sup> Essentially independent of operating temperature.

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

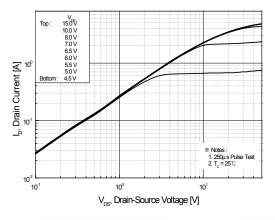


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

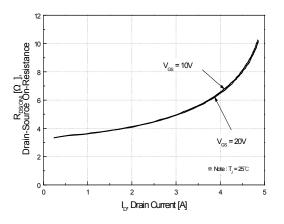


Figure 5. Capacitance Characteristics

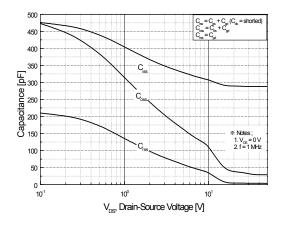


Figure 2. Transfer Characteristics

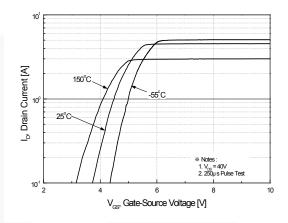
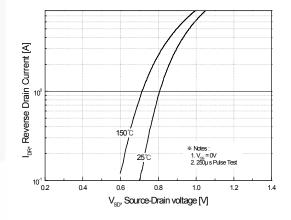
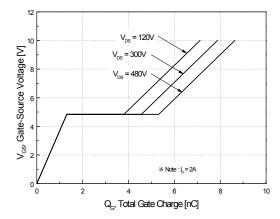


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue



**Figure 6. Gate Charge Characteristics** 



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

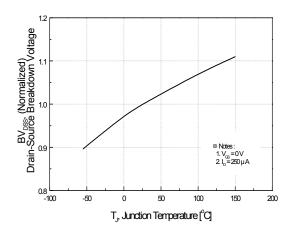


Figure 9. Maximum Safe Operating Area

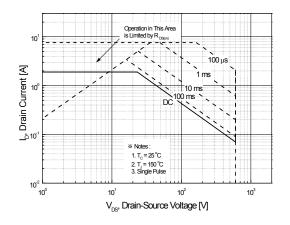


Figure 8. On-Resistance Variation vs. Temperature

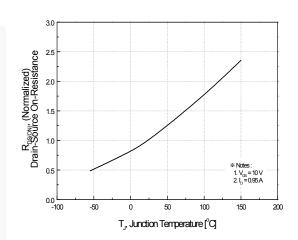


Figure 10. Maximum Drain Current vs. Case Temperature

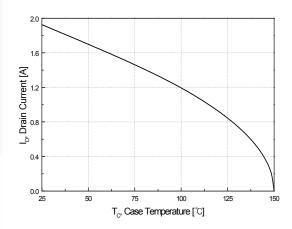


Figure 11. Transient Thermal Response Curve

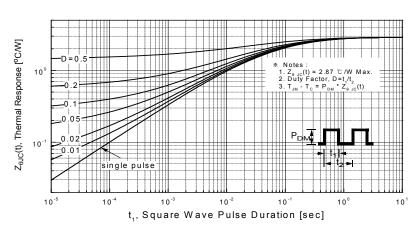


Figure 12. Gate Charge Test Circuit & Waveform

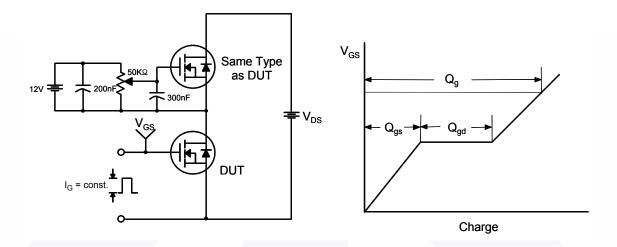


Figure 13. Resistive Switching Test Circuit & Waveforms

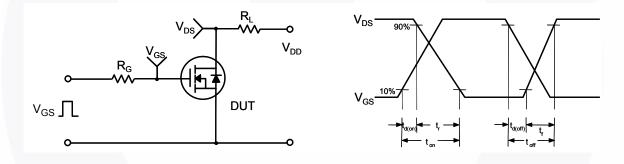
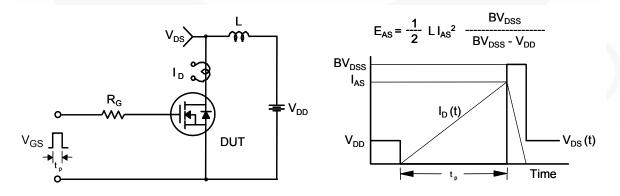


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



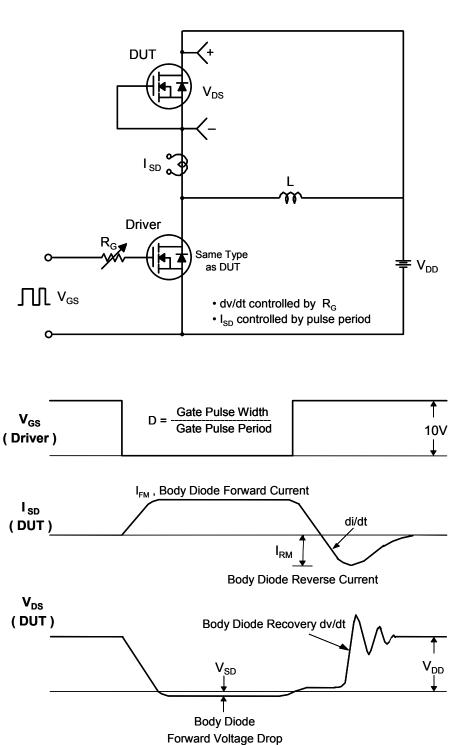
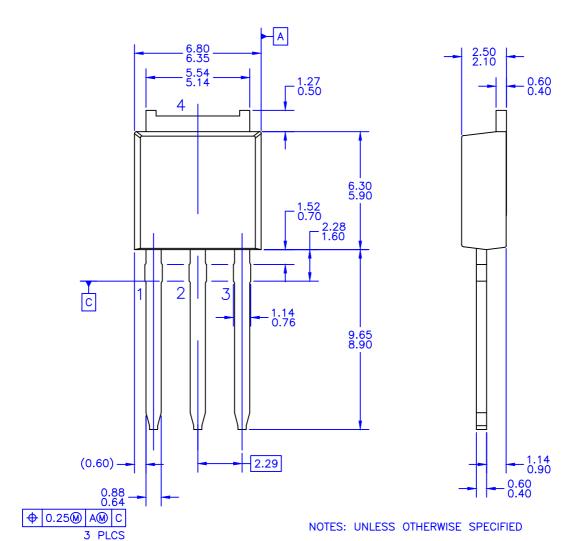
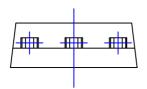


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms





- - ALL DIMENSIONS ARE IN MILLIMETERS.
- B) THIS PACKAGE CONFORMS TO JEDEC, TO-251, ISSUE C, VARIATION AA, DATED SEP 1988.
  C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
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